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1 Integrated flow-thermomechanical and reliability analysis of a densely packed C4/CBGA assembly

Hong, B.Z.; Yuan, T.-D.;

Thermal and Thermomechanical Phenomena in Electronic Systems, 1998. ITHERM '98. The Sixth Intersociety Conference on , 27-30 May 1998

Pages:220 - 228

[Abstract]

[PDF Full-Text (876 KB)] **IEEE CNF**

2 Flip-chip interconnection technology for advanced thermal conduction modules

Ray, S.K.; Beckham, K.; Master, R.;

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Pages:772 - 778

[PDF Full-Text (544 KB)] IEEE CNF [Abstract]

3 FCOB reliability evaluation simulating multiple rework/reflow processes Wayne Chen;

Components, Packaging, and Manufacturing Technology, Part C, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transactions on], Volume: 19, Issue: 4, Oct. 1996

Pages: 270 - 276

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Kromann, G.B.; Gerke, R.D.; Wayne Wei-Xi Huang; Components, Packaging, and Manufacturing Technology, Part B: Advanced Packaging, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transactions on], Volume: 19, Issue: 1, Feb. 1996

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Pages: 166 - 173

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5 Effect f package design and layout n BGAs Iderj int reliability of an organic C4 package

Chandran, B.; Goyal, D.; Thomas, J.;

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10 Design-based thermal simulation methodology for ball grid array packages

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11 A low-cost ceramic BGA package for 50 Gb/s multiplexing circuit

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Shan, L.; Trewhella, J.; Baks, C.; John, R.; Dyckman, W.; O'Connor, D.; Pillai, E.; Electrical Performance of Electronic Packaging, 2003, 27-29 Oct. 2003 Pages: 59 - 62

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